

Issue Classification		Application/Control No. 10/624,173				Applicant(s)/Patent under Reexamination BAUMANN ET AL.	
		Examiner Devin Hanan				Art Unit 3745	

ISSUE CLASSIFICATION											
ORIGINAL				INTERNATIONAL CLASSIFICATION							
CLASS		SUBCLASS		CLAIMED			NON-CLAIMED				
415		202		F	01	D	1 /08				/
CROSS REFERENCES											/
CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)									/
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<i>Devin Hanan 10/29/07</i> Devin Hanan 10/29/2007 (Assistant Examiner) (Date)				<i>Edward K. Look</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER (Technology Center 3700) <i>10/11/07</i>				Total Claims Allowed: 8			
(Legal Instruments Examiner) (Date)								O.G. Print Claim(s)		O.G. Print Fig.	
								1		1	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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